

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Chen, *et al.* Attorney Docket: 2001 P 11914 US
Filed: September 28, 2001 Examiner: Unknown
Serial No.: 09/965,093 Art Unit: 2812
Title: DIRECT, NON-DESTRUCTIVE MEASUREMENT OF RECESS DEPTH
IN A WAFER

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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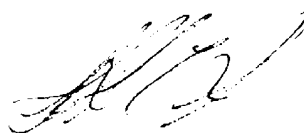
Associate Power of Attorney

I hereby appoint as associate attorneys of record all of the attorneys and agents at
Customer Number 25962.

Also please direct all future correspondence to:

Ira S. Matsil
Slater & Matsil, L.L.P.
17950 Preston Road, Suite 1000
Dallas, TX 75252
(972) 732-1001
(972) 732-9218 (fax)

Respectfully submitted,



Stanton C. Braden
Attorney for Applicants
Reg. No. 32,556

Infineon Technologies North America Corp.
Intellectual Property Department, 5th Floor
170 Wood Avenue S.
Iselin, NJ 08830